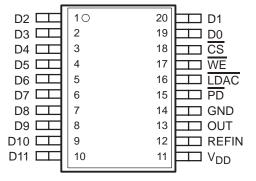
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- Controlled Baseline
  - One Assembly/Test Site, One Fabrication Site
- Extended Temperature Performance of -40°C to 125°C
- Enhanced Diminishing Manufacturing Sources (DMS) Support
- Enhanced Product Change Notification
- Qualification Pedigree<sup>†</sup>
- Single Supply 2.7-V to 5.5-V Operation
- ±0.4 LSB Differential Nonlinearity (DNL),
   ±1.5 LSB Integral Nonlinearity (INL)
- 12-Bit Parallel Interface
- Compatible With TMS320 DSP
- Internal Power On Reset
- Settling Time 1 μs Typ
- Low Power Consumption:
  - 8 mW for 5-V Supply
  - 4.3 mW for 3-V Supply
- Reference Input Buffers
- Voltage Output
- Monotonic Over Temperature
- Asynchronous Update

## applications

- Battery Powered Test Instruments
- Digital Offset and Gain Adjustment
- Battery Operated/Remote Industrial Controls
- Machine and Motion Control Devices
- Cordless and Wireless Telephones
- Speech Synthesis
- Communication Modulators
- Arbitrary Waveform Generation

# DW PACKAGE (TOP VIEW)



## description

The TLV5619 is a 12-bit voltage output DAC with a microprocessor and TMS320 compatible parallel interface. The 12 data bits are double buffered so that the output can be updated asynchronously using the LDAC pin. During normal operation, the device dissipates 8 mW at a 5-V supply and 4.3 mW at a 3-V supply. The power consumption can be lowered to 50 nW by setting the DAC to power-down mode.

The output voltage is buffered by a ×2 gain rail-to-rail amplifier, which features a Class A output stage to improve stability and reduce settling time.

#### ORDERING INFORMATION

TA	PACKAGE <sup>‡</sup>		ORDERABLE PART NUMBER	TOP-SIDE MARKING
-40°C to 125°C	SOP – DW	Tape and reel	TLV5619QDWREP	TLV5619QEP

<sup>&</sup>lt;sup>‡</sup> Package drawings, standard packing quantities, thermal data, symbolization, and PCB design guidelines are available at www.ti.com/sc/package.



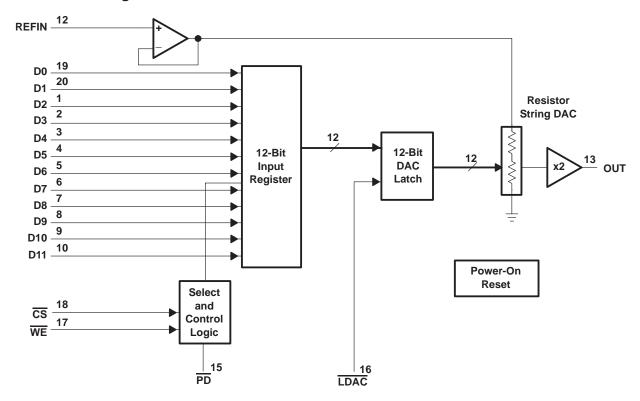
Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.



<sup>†</sup> Component qualification in accordance with JEDEC and industry standards to ensure reliable operation over an extended temperature range. This includes, but is not limited to, Highly Accelerated Stress Test (HAST) or biased 85/85, temperature cycle, autoclave or unbiased HAST, electromigration, bond intermetallic life, and mold compound life. Such qualification testing should not be viewed as justifying use of this component beyond specified performance and environmental limits.

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# functional block diagram



## **Terminal Functions**

TERMINAL			DECORPTION
NAME	NO.	1/0	DESCRIPTION
CS	18	-1	Chip select
D0 (LSB)-D11 (MSB)	19, 20, 1 – 10	-1	Parallel data input
GND	14		Ground
LDAC	16	-1	Load DAC
OUT	13	0	Analog output
PD	15	ı	When low, disables all buffer amplifier voltages to reduce supply current
REFIN	12	-1	Voltage reference input
$V_{DD}$	11		Positive power supply
WE	17	I	Write enable



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# absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†

Supply voltage (V <sub>DD</sub> to GND)	
Analog input voltage range	
Reference input voltage	V <sub>DD</sub> + 0.3 V
Digital input voltage range to GND	– 0.3 V to V <sub>DD</sub> + 0.3 V
Operating free-air temperature range, T <sub>A</sub> :	–40°C to 125°C
Storage temperature range, T <sub>stq</sub>	–65°C to 150°C
Lead temperature 1,6 mm (1/16 inch) from case for 10 seconds	

<sup>†</sup> Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

# recommended operating conditions

		MIN	NOM	MAX	UNIT
Supply voltage, V <sub>DD</sub> (5-V Supply)		4.5	5	5.5	V
Supply voltage, V <sub>DD</sub> (3-V Supply)		2.7 3 3.3			V
High level digital input value of M	V <sub>DD</sub> = 2.7 V	2			
igh-level digital input voltage, V <sub>IH</sub>	V <sub>DD</sub> = 5.5 V	2.4			V
Louis louis digital input valtage. Viv	V <sub>DD</sub> = 2.7 V			0.6	
Low-level digital input voltage, V <sub>IL</sub>	V <sub>DD</sub> = 5.5 V			0.8	V
Reference voltage, V <sub>ref</sub> to REFIN terminal (	i-V Supply)	0	2.048	V <sub>DD</sub> -1.5	V
Reference voltage, V <sub>ref</sub> to REFIN terminal (	B-V Supply)	0	1.024	V <sub>DD</sub> -1.5	V
Load resistance, R <sub>L</sub>		2	10		kΩ
Load capacitance, CL				100	pF
Operating free-air temperature, TA		-40		125	°C

NOTES: 1. The recommended operating levels for both  $V_{IH}$  and  $V_{IL}$  apply to all valid values of  $V_{DD}$ .



<sup>2.</sup> Reference input voltages greater than  $\mbox{V}_{\mbox{DD}}/\mbox{2}$  will cause output saturation for large DAC codes.

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electrical characteristics over recommended operating free-air temperature range, supply voltages, and reference voltages (unless otherwise noted)

## static DAC specifications

	PARAMETER		TEST CONDITION	S	MIN	TYP	MAX	UNIT
	Resolution		V <sub>ref</sub> (REFIN) = 2.048 V at 5 V, 1.024 V at 3 V		12			bits
	Integral nonlinearity (INL)		V <sub>ref(REFIN)</sub> = 2.048 V at 5 V, 1.024 V at 3 V,	See Note 3		±1.5	±4	LSB
	Differential nonlinearity (DNL)		V <sub>ref</sub> (REFIN) = 2.048 V at 5 V, 1.024 V at 3 V,	See Note 4		± 0.4	± 1	LSB
EZS	Zero-scale error (offset error a	ero-scale error (offset error at zero scale)		See Note 5		±3	±20	mV
	Zero-scale-error temperature of	coefficient	V <sub>ref(REFIN)</sub> = 2.048 V at 5 V, 1.024 V at 3 V,	See Note 6		3		ppm/°C
EG	Gain error		Vref(REFIN) = 2.048 V at 5 V, 1.024 V at 3 V,	See Note 7		±0.25	±0.5	% of FS voltage
	Gain error temperature coefficient		V <sub>ref</sub> (REFIN) = 2.048 V at 5 V, 1.024 V at 3 V,	See Note 8		1		ppm/°C
Debb	PSRR Power-supply rejection ratio  Zero scale  Gain  See Note:		See Notes 9 and 10			65		dB
FORK			See Notes a and 10		65			ub

- NOTES: 3. The relative accuracy or integral nonlinearity (INL), sometimes referred to as linearity error, is the maximum deviation of the output from the line between zero and full scale excluding the effects of zero code and full-scale errors.
  - 4. The differential nonlinearity (DNL), sometimes referred to as differential error, is the difference between the measured and ideal 1 LSB amplitude change of any two adjacent codes. Monotonic means the output voltage changes in the same direction (or remains constant) as a change in the digital input code.
  - 5. Zero-scale error is the deviation from zero voltage output when the digital input code is zero.
  - 6. Zero-scale-error temperature coefficient is given by:  $E_{ZS}$  TC =  $[E_{ZS}$  ( $T_{max}$ )  $E_{ZS}$  ( $T_{min}$ )]/ $V_{ref}$  × 10<sup>6</sup>/( $T_{max}$   $T_{min}$ ).
  - 7. Gain error is the deviation from the ideal output (2 × V<sub>ref</sub> 1 LSB) with an output load of 10 kΩ excluding the effects of the zero-error.
  - 8. Gain temperature coefficient is given by:  $E_G TC = [E_G(T_{max}) E_G(T_{min})]/V_{ref} \times 10^6/(T_{max} T_{min})$ .
  - 9. Zero-scale-error rejection ratio (EZS-RR) is measured by varying the V<sub>DD</sub> from 4.5 V to 5.5 V dc and measuring the proportion of this signal imposed on the zero-code output voltage.
  - 10. Gain-error rejection ratio (EG-RR) is measured by varying the V<sub>DD</sub> from 4.5 V to 5.5 V dc and measuring the proportion of this signal imposed on the full-scale output voltage after subtracting the zero scale change.

#### output specifications

	PARAMETER	TEST CONDITION	MIN	TYP	MAX	UNIT		
VO	Voltage output range	$R_L = 10 \text{ k}\Omega$		0		V <sub>DD</sub> -0.4	V	
	Output load regulation accuracy	V <sub>O</sub> (OUT) = 4.096 V, 2.048 V	R <sub>L</sub> = 2 kΩ		0.1	0.29	% of FS voltage	
laasi ,	Output about sircuit source surrent	$V_{O(OUT)} = 0 V,$	5-V Supply		100		A	
IOSC(source)	Output short circuit source current	Full`scalé code	3-V Supply		25		mA	
1	Output course oursest	D. 400.0	5-V Supply		10		A	
<sup>I</sup> O(source)	Output source current	R <sub>L</sub> = 100 Ω	3-V Supply		10	·	mA	



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electrical characteristics over recommended operating free-air temperature range, supply voltages, and reference voltages (unless otherwise noted)

## reference input (REFIN)

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
V <sub>ref</sub>	Reference input voltage	See Note 11	0		V <sub>DD</sub> -1.5	V
Ri	Reference input resistance			10		$M\Omega$
Ci	Reference input capacitance			5		pF
	Reference feed through	REFIN = 1 V <sub>pp</sub> at 1 kHz + 1.024 V dc (see Note 12)		-60		dB
	Reference input bandwidth	REFIN = 0.2 V <sub>pp</sub> + 1.024 V dc at –3 dB		1.4		MHz

NOTES: 11. Reference input voltages greater than  $V_{DD}/2$  will cause output saturation for large DAC codes.

# digital inputs (D0 - D11, CS, WE, LDAC, PD)

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
lн	High-level digital input current	$V_I = V_{DD}$			1	μΑ
IIL	Low-level digital input current	V <sub>I</sub> = 0 V			-1	μΑ
Ci	Input capacitance			8		pF

## power supply

	PARAMETER	TEST CONDITIONS			TYP	MAX	UNIT
I Davida avantu avant		No local Allianata O.V. an V.	5-V Supply		1.6	3	4
IDD	Power supply current	No load, All inputs 0 V or V <sub>DD</sub>	3-V Supply		1.44	2.7	mA
	Power down supply current				0.01	10	μΑ

<sup>12.</sup> Reference feedthrough is measured at the DAC output with an input code = 0x000 and a V<sub>ref(REFIN)</sub> input = 1.024 V dc + 1 V<sub>pp</sub> at 1 kHz.

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operating characteristics over recommended operating free-air temperature range, supply voltages, and reference voltages (unless otherwise noted)

# analog output dynamic performance

	PARAMETER	TES	T CONDITIONS		MIN	TYP	MAX	UNIT
CD.	$C_L = 100 \text{ pF},$ $V_{ref(REFIN)} = 2.048 \text{ V},$ $Supply$		I	8	12		V/μs	
SR	Slew rate	Code 32 to code 4095, Code 4095 to code 32,	V <sub>O</sub> from 10% to 90% 90% to 10%	3-V Supply	6	9		V/μs
t <sub>S</sub>	Output settling time (full scale)	To $\pm 0.5$ LSB, R <sub>L</sub> = 10 kΩ,				1	3	μs
	Glitch energy	DIN = all 0s to all 1s				5		nV-s
S/N	Signal to noise	f <sub>S</sub> = 480 kSPS, BW = 20 kHz, C <sub>L</sub> = 100 pF,	$f_{OUT}$ = 1 kHz, R <sub>L</sub> = 10 kΩ T <sub>A</sub> = 25°C, See Note 14	5-V Supply	65	78		
S/(N+D)	Signal to point a distortion	f <sub>S</sub> = 480 kSPS, BW = 20 kHz,	$f_{OUT} = 1 \text{ kHz},$ $R_L = 10 \text{ k}\Omega,$	5-V Supply	58	67		
3/(N+D)	Signal to noise + distortion	C <sub>L</sub> = 100 pF,	$T_A = 25^{\circ}C$ , See Note 14	3-V Supply	58	69		dB
	Total harmonic distortion	f <sub>S</sub> = 480 kSPS, BW = 20 kHz, C <sub>L</sub> = 100 pF,	$f_{OUT} = 1 \text{ kHz},$ $R_L = 10 \text{ k}\Omega,$ $T_A = 25^{\circ}\text{C}$ , See Note 14			-68	-60	
	Spurious free dynamic range	f <sub>S</sub> = 480 kSPS, BW = 20 kHz, C <sub>L</sub> = 100 pF,	$f_{OUT} = 1 \text{ kHz},$ $R_L = 10 \text{ k}\Omega,$ $T_A = 25^{\circ}\text{C}$ , See Note 14		60	72		

NOTES: 13. Settling time is the time for the output signal to remain within ±0.5 LSB of the final measured value for a digital input code change of 0x020 to 0x3DF or 0x3DF to 0x020. Limits are ensured by design and characterization, but are not production tested.

## timing requirement

#### digital inputs

		MIN	NOM	MAX	UNIT
t <sub>su(CS-WE)</sub>	Setup time, CS low before positive WE edge	13			ns
t <sub>su(D)</sub>	Setup time, data ready before positive WE edge	9			ns
t <sub>h(D)</sub>	Hold time, data held after positive WE edge	0			ns
t <sub>su(WE-LD)</sub>	Setup time, positive WE edge before LDAC low	0			ns
twh(WE)	Pulse width, WE high	25			ns
t <sub>w(LD)</sub>	Pulse width, LDAC low	25			ns



<sup>14. 1</sup> kHz sinewave generated by DAC, reference voltage = 1.024 V at 3 V and 2.048 V at 5 V.

# PARAMETER MEASUREMENT INFORMATION

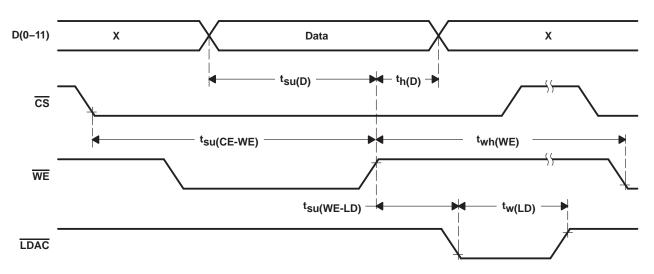
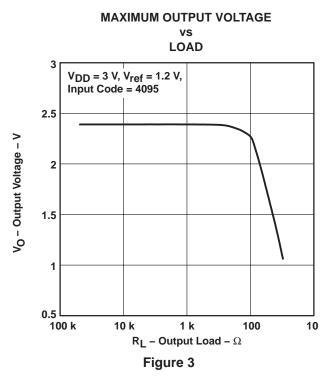


Figure 1. Timing Diagram

#### TYPICAL CHARACTERISTICS

# **MAXIMUM OUTPUT VOLTAGE** VS LOAD $V_{DD} = 5 \text{ V}, V_{ref} = 2 \text{ V},$ Input Code = 4095 V<sub>O</sub> - Output Voltage - V 3 2 10 k 100 100 k 1 k 10 $R_L$ – Output Load – $\Omega$

Figure 2



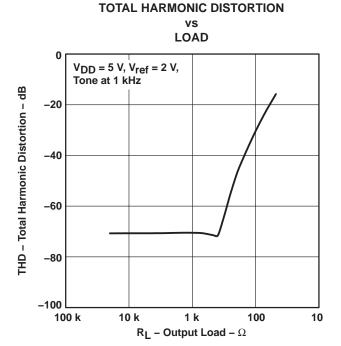
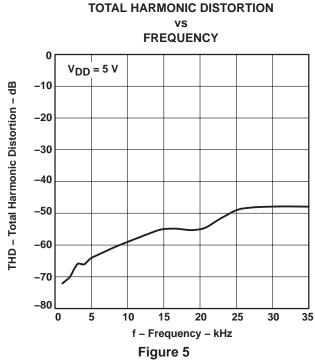


Figure 4



# **TYPICAL CHARACTERISTICS**

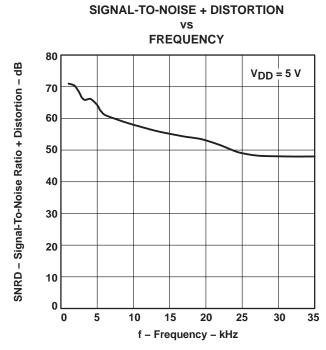
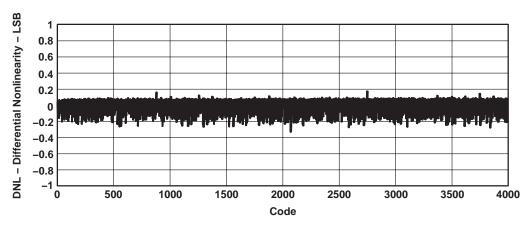


Figure 6



**Figure 7. Differential Nonlinearity** 

# **TYPICAL CHARACTERISTICS**

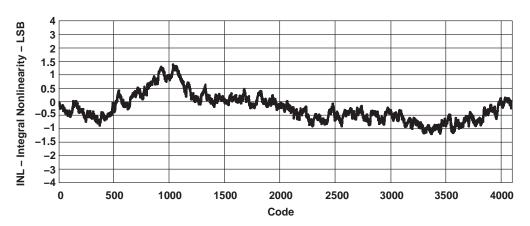


Figure 8. Integral Nonlinearity

# POWER DOWN SUPPLY CURRENT

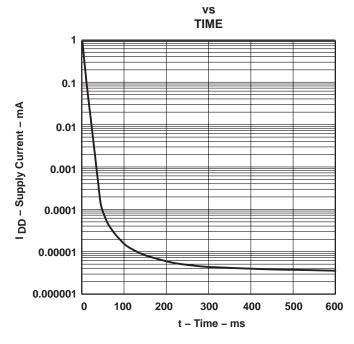


Figure 9

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#### APPLICATION INFORMATION

## definitions of specifications and terminology

## integral nonlinearity (INL)

The relative accuracy or integral nonlinearity (INL), sometimes referred to as linearity error, is the maximum deviation of the output from the line between zero and full scale excluding the effects of zero code and full-scale errors.

## differential nonlinearity (DNL)

The differential nonlinearity (DNL), sometimes referred to as differential error, is the difference between the measured and ideal 1 LSB amplitude change of any two adjacent codes. Monotonic means the output voltage changes in the same direction (or remains constant) as a change in the digital input code.

## zero-scale error (EZS)

Zero-scale error is defined as the deviation of the output from 0 V at a digital input value of 0.

### gain error (E<sub>G</sub>)

Gain error is the error in slope of the DAC transfer function.

## signal-to-noise ratio + distortion (S/N+D)

S/N+D is the ratio of the rms value of the output signal to the rms sum of all other spectral components below the Nyquist frequency, including harmonics but excluding dc. The value for S/N+D is expressed in decibels.

## spurious free dynamic range (SFDR)

SFDR is the difference between the rms value of the output signal and the rms value of the largest spurious signal within a specified bandwidth. The value for SFDR is expressed in decibels.

#### total harmonic distortion (THD)

THD is the ratio of the rms sum of the first six harmonic components to the rms value of the fundamental signal and is expressed in decibels.



#### APPLICATION INFORMATION

## linearity, offset, and gain error using single end supplies

When an amplifier is operated from a single supply, the voltage offset can still be either positive or negative. With a positive offset, the output voltage changes on the first code change. With a negative offset the output voltage may not change with the first code depending on the magnitude of the offset voltage.

The output amplifier attempts to drive the output to a negative voltage. However, because the most negative supply rail is ground, the output cannot drive below ground and clamps the output at 0 V.

The output voltage remains at zero until the input code value produces a sufficient positive output voltage to overcome the negative offset voltage, resulting in the transfer function shown in Figure 10.

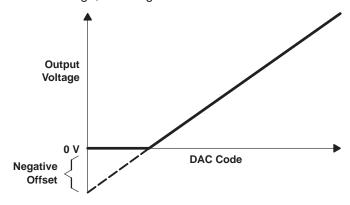


Figure 10. Effect of Negative Offset (Single Supply)

This offset error, not the linearity error, produces this breakpoint. The transfer function would have followed the dotted line if the output buffer could drive below the ground rail.

For a DAC, linearity is measured between zero input code (all inputs 0) and full scale code (all inputs 1) after offset and full scale are adjusted out or accounted for in some way. However, single supply operation does not allow for adjustment when the offset is negative due to the breakpoint in the transfer function. So the linearity is measured between full scale code and the lowest code that produces a positive output voltage.

## general function

The TLV5619 is a 12-bit, single supply DAC, based on a resistor string architecture. It consists of a parallel interface, a power down control logic, a resistor string, and a rail-to-rail output buffer. The output voltage (full scale determined by reference) is given by:

$$2 REF \frac{CODE}{0x1000} [V]$$

Where REF is the reference voltage and CODE is the digital input value, range 0x000 to 0xFFF. A power on reset initially puts the internal latches to a defined state (all bits zero).



#### **APPLICATION INFORMATION**

## parallel interface

The device latches data on the positive edge of  $\overline{\text{WE}}$ . It must be enabled with  $\overline{\text{CS}}$  low.  $\overline{\text{LDAC}}$  low updates the DAC with the value in the holding latch.  $\overline{\text{LDAC}}$  is an asynchronous input and can be held low, if a separate update is not necessary. However, to control the DAC using the load feature,  $\overline{\text{LDAC}}$  can be driven low after the positive  $\overline{\text{WE}}$  edge.

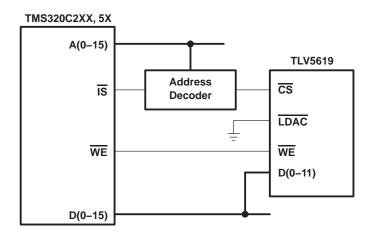


Figure 11. Proposed Interface Between TLV5619 and TMS320C2XX, 5X DSPs

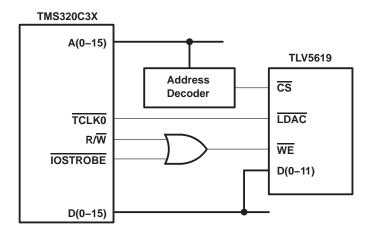


Figure 12. Proposed Interface Between TLV5619 and TMS320C3X DSPs

#### **APPLICATION INFORMATION**

### TLV5619 interfaced to TMS320C203 DSP

#### hardware interface

Figure 13 shows an example of the connection between the TLV5619 and the TMS320C203 DSP. The only other device that is needed in addition to the DSP and the DAC is the 74AC138 address decoding circuit . Using this configuration, the DAC address is 0x0084 within the I/O memory space of the TMS320C203.

 $\overline{\text{LDAC}}$  is held low so that the output voltage is updated with the rising  $\overline{\text{WE}}$  edge. The power down mode is deactivated permanently by pulling  $\overline{\text{PD}}$  to  $V_{DD}$ .

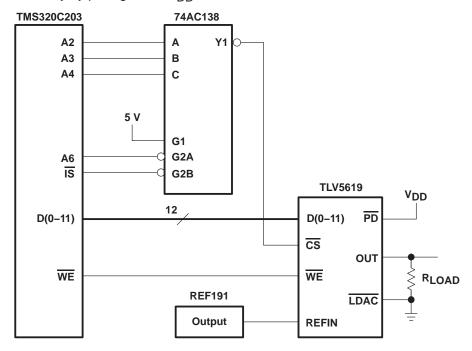


Figure 13. TLV5619 to TMS320C203 DSP Interface Connection

#### software

No setup procedure is needed to access the TLV5619. The output voltage can be set using one command:

Where data\_addr points to the address location (in this example 0x0060) holding the new output voltage data and DAC addr is the I/O space address of the TLV5619 (in this example 0x0084).

The following code shows, how to use the timer of the TMS320C203 as a time base to generate a voltage ramp with the TLV5619. A timer interrupt is generated every 205  $\mu$ s. The corresponding interrupt service routine increments the output code (stored at 0x0060) for the DAC and writes the new code to the TLV5619. Only the 12 LSBs of the data in 0x0060 are used by the DAC, so that the resulting period of the saw waveform is:

 $\tau = 4096 \times 205 \text{ E-6 s} = 0.84 \text{ s}$ 



#### APPLICATION INFORMATION

#### software listing

```
; File: ramp.asm
; Description: This program generates a ramp.
;----- I/O and memory mapped regs -----
       .include "regs.asm"
TLV5619
       .equ 0084h
;----- vectors ------
        .ps
            0h
        b
             start
        b
             INT1
             TNT23
       h
        b
             TIM ISR
*******************
* Main Program
*******************
             1000h
       .ps
        .entry
start:
             #0
       ldp
                  ; set data page to 0
; disable interrupts
        setc
             INTM
                 ; disable maskable interrupts
             #Offffh, IFR
        splk
        splk
             #0004h,
                     IMR
; set up the timer
             #0000h,
        splk
                     60h
       splk
             #0042h,
                     61h
             61h, PRD
60h, TIM
        out
        out
             60n, _
#0c2fh, &
TCR
                     62h
        splk
        out
; enable interrupts
            INTM ; enable maskable interrupts
        clrc
; loop forever!
       idle
                  ; wait for interrupt
       b
               next
; all else fails stop here
               done ; hang there
done
       h
*******************
* Interrupt Service Routines
****************
TNT1 ·
      ret
                  ; do nothing and return
INT23:
                  ; do nothing and return
      ret
TIM ISR:
     ; useful code
                #1h ; increment accumulator
        add
        sacl
                  60h, TLV5619; write to DAC
        out
                intm; re-enable interrupts
        clrc
        ret
                   ; return from interrupt
        .end
```







ti.com 18-Sep-2008

#### **PACKAGING INFORMATION**

Orderable Device	Status <sup>(1)</sup>	Package Type	Package Drawing	Pins F	Package Qty	e Eco Plan <sup>(2)</sup>	Lead/Ball Finish	MSL Peak Temp <sup>(3)</sup>
TLV5619QDWREP	ACTIVE	SOIC	DW	20	2000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM
V62/03615-01XE	ACTIVE	SOIC	DW	20	2000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM

<sup>(1)</sup> The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

**NRND**: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

**PREVIEW:** Device has been announced but is not in production. Samples may or may not be available.

**OBSOLETE:** TI has discontinued the production of the device.

(2) Eco Plan - The planned eco-friendly classification: Pb-Free (RoHS), Pb-Free (RoHS Exempt), or Green (RoHS & no Sb/Br) - please check http://www.ti.com/productcontent for the latest availability information and additional product content details.

TBD: The Pb-Free/Green conversion plan has not been defined.

**Pb-Free** (RoHS): TI's terms "Lead-Free" or "Pb-Free" mean semiconductor products that are compatible with the current RoHS requirements for all 6 substances, including the requirement that lead not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, TI Pb-Free products are suitable for use in specified lead-free processes.

**Pb-Free (RoHS Exempt):** This component has a RoHS exemption for either 1) lead-based flip-chip solder bumps used between the die and package, or 2) lead-based die adhesive used between the die and leadframe. The component is otherwise considered Pb-Free (RoHS compatible) as defined above.

**Green (RoHS & no Sb/Br):** TI defines "Green" to mean Pb-Free (RoHS compatible), and free of Bromine (Br) and Antimony (Sb) based flame retardants (Br or Sb do not exceed 0.1% by weight in homogeneous material)

(3) MSL, Peak Temp. -- The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.

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### OTHER QUALIFIED VERSIONS OF TLV5619-EP:

Catalog: TLV5619

NOTE: Qualified Version Definitions:

Catalog - TI's standard catalog product

16-Jul-2008

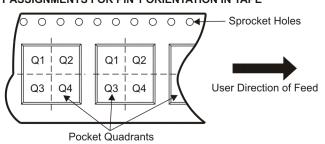
## TAPE AND REEL INFORMATION





A0	Dimension designed to accommodate the component width
B0	Dimension designed to accommodate the component length
K0	Dimension designed to accommodate the component thickness
W	Overall width of the carrier tape
P1	Pitch between successive cavity centers

QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE



\*All dimensions are nominal

Device		Package Drawing			Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
TLV5619QDWREP	SOIC	DW	20	2000	330.0	24.4	10.8	13.1	2.65	12.0	24.0	Q1





#### \*All dimensions are nominal

ĺ	Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
I	TLV5619QDWREP	SOIC	DW	20	2000	346.0	346.0	41.0

# DW (R-PDSO-G20)

# PLASTIC SMALL-OUTLINE PACKAGE



NOTES:

- A. All linear dimensions are in inches (millimeters).
- B. This drawing is subject to change without notice.
- C. Body dimensions do not include mold flash or protrusion not to exceed 0.006 (0,15).
- D. Falls within JEDEC MS-013 variation AC.





# PACKAGE OPTION ADDENDUM

31-May-2014

#### **PACKAGING INFORMATION**

Orderable Device	Status	Package Type	Package Drawing	Pins	Package Qty	Eco Plan	Lead/Ball Finish	MSL Peak Temp	Op Temp (°C)	Device Marking (4/5)	Samples
TLV5619QDWREP	ACTIVE	SOIC	DW	20	2000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 125	TLV5619QEP	Samples
V62/03615-01XE	ACTIVE	SOIC	DW	20	2000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 125	TLV5619QEP	Samples

(1) The marketing status values are defined as follows:

**ACTIVE:** Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

**OBSOLETE:** TI has discontinued the production of the device.

(2) Eco Plan - The planned eco-friendly classification: Pb-Free (RoHS), Pb-Free (RoHS Exempt), or Green (RoHS & no Sb/Br) - please check http://www.ti.com/productcontent for the latest availability information and additional product content details.

**TBD:** The Pb-Free/Green conversion plan has not been defined.

**Pb-Free** (RoHS): TI's terms "Lead-Free" or "Pb-Free" mean semiconductor products that are compatible with the current RoHS requirements for all 6 substances, including the requirement that lead not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, TI Pb-Free products are suitable for use in specified lead-free processes.

**Pb-Free (RoHS Exempt):** This component has a RoHS exemption for either 1) lead-based flip-chip solder bumps used between the die and package, or 2) lead-based die adhesive used between the die and leadframe. The component is otherwise considered Pb-Free (RoHS compatible) as defined above.

Green (RoHS & no Sb/Br): TI defines "Green" to mean Pb-Free (RoHS compatible), and free of Bromine (Br) and Antimony (Sb) based flame retardants (Br or Sb do not exceed 0.1% by weight in homogeneous material)

- (3) MSL, Peak Temp. The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.
- (4) There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.
- (5) Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.
- (6) Lead/Ball Finish Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead/Ball Finish values may wrap to two lines if the finish value exceeds the maximum column width.

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# **PACKAGE OPTION ADDENDUM**

31-May-2014

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#### OTHER QUALIFIED VERSIONS OF TLV5619-EP:

NOTE: Qualified Version Definitions:

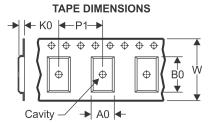
• Catalog - TI's standard catalog product

**PACKAGE MATERIALS INFORMATION** 

www.ti.com 20-Feb-2019

# TAPE AND REEL INFORMATION





	Dimension designed to accommodate the component width
В0	Dimension designed to accommodate the component length
K0	Dimension designed to accommodate the component thickness
W	Overall width of the carrier tape
P1	Pitch between successive cavity centers

## QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE



## \*All dimensions are nominal

Device	Package Type	Package Drawing			Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
TLV5619QDWREP	SOIC	DW	20	2000	330.0	24.4	10.8	13.3	2.7	12.0	24.0	Q1

**PACKAGE MATERIALS INFORMATION** 

www.ti.com 20-Feb-2019



#### \*All dimensions are nominal

Device	evice Package Type		Pins	SPQ	Length (mm)	Width (mm)	Height (mm)	
TLV5619QDWREP	SOIC	DW	20	2000	350.0	350.0	43.0	



SOIC



## NOTES:

- 1. All linear dimensions are in millimeters. Dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.

  2. This drawing is subject to change without notice.

  3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not
- exceed 0.15 mm per side.
- 4. This dimension does not include interlead flash. Interlead flash shall not exceed 0.43 mm per side.
- 5. Reference JEDEC registration MS-013.



SOIC



NOTES: (continued)

6. Publication IPC-7351 may have alternate designs.

7. Solder mask tolerances between and around signal pads can vary based on board fabrication site.



SOIC



NOTES: (continued)

- 8. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
- 9. Board assembly site may have different recommendations for stencil design.



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